



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242823US2RD		SERIAL NO. 10/661,593	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shinichi YASUDA, et al.			
				FILING DATE September 15, 2003		GROUP <del>2016</del> 2193	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/CD/	AO	2002-41281	02/08/2002	JAPAN (with English Abstract)			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Chat Do/ (04/14/2007)					Date Considered 04/14/2007		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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## LIST OF REFERENCES CITED BY APPLICANT

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Shinichi YASUDA, et al.FILING DATE  
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## U.S. PATENT DOCUMENTS

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	AA						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/CD/	AO	2002-24000	01/25/2002	JAPAN		X
/CD/	AP	63-173922	11/11/1988	JAPAN		X
	AQ					
	AR					
	AS					
	AT					
	AU					
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
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☐ Additional References sheet(s) attached

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## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Shinichi YASUDA, et al.

FILING DATE

September 15, 2003

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/CD/	AO	9-146761	06/06/1997	JAPAN (with English Abstract)		X
	AP					
	AQ					
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

/CD/	AW	Patent Abstracts of Japan, JP 2002-024000, January 25, 2002 (submitting English Abstract only, reference previously filed in Japanese language on 02/28/05)				
	AX					
	AY					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	

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				GROUP <del>2846</del> 2193			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/CD/	AA	3,866,029	02/11/1975	Paul Chevalier			
/CD/	AB	3,716,796	02/13/1973	Hyacinth E. HARNA			
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/CD/	AO	1 239 363 A2	09/11/2002	EUROPE			
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/CD/	AW	Tanemasa ASANO, et al., "Physical Random-Number Generator Using Schottky MOSFET", Extended Abstracts of the 2001 International Conference on Solid State Devices and Materials, Japan Society of Applied Physics, vol. 2001, XP-001074511, September 26, 2001, pages 96-97					
/CD/	AX	Craig S. PETRIE, et al., "A Noise-Based IC Random Number Generator for Applications in Cryptography", IEEE Transactions on Circuits and Systems-I: Fundamental Theory and Applications, vol. 47, no. 5, XP-001124059, May 2000, pages 615-621					
/CD/	AY	Benjamin JUN, et al., "The Intel Random Number Generator", Cryptographic Research, XP-002361777, April 22, 1999, pages 1-8					
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
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